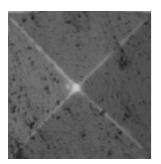
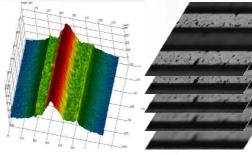


Compact 3D Digital Microscope

- High Resolution Digital Microscopy
- Accurate Z Depth Measurement
- Fast 3D Acquisition and Analysis
- Automatic Depth Composition
- 3D Surface Metrology









PORTABLE 3D DIGITAL MICROSCOPE

The Easiest Way To 3D Imaging

Applications:

3D Image documentation

Z-Stacking

Extended depth of field

3D Shane

Image fusior

Roughness

Z Depth measurement

Surface Metrology

Labs & Field Inspection

Metal Tooling

Forensics

Printing

Archeology

Educatio

Electronic:

Semiconductor

Museun

Automotive

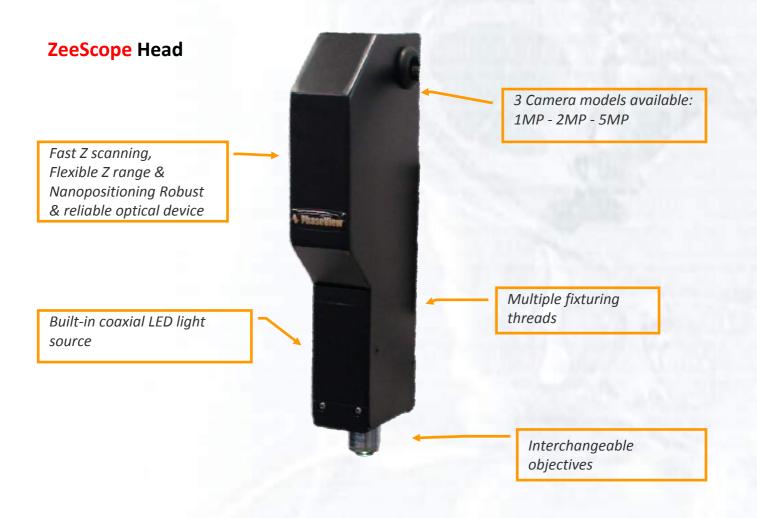
Aeropace

Genlogy

- No Moving Parts
- All-In-One Device
- Maintenance Free •
- No Costly Accessories
- User Friendly Software







ZeeScope Control Unit





Optional Lithium battery for Field autonomy

ZeeScope Applications

Light Portable Microscope For Field Inspection

- ✓ On site Quality Control
- ✓ Field Inspection
- ✓ Maintenance





Accurate 3D Microscope For Labs & Shop Floor

- ✓ Shop Floor Rapid Testing
- ✓ R&D Labs
- ✓ QC Laboratories

3D Industrial Quality Control

- ✓ Manufacturing Quality Control
- ✓ Shop Floor Diagnostic Tool
- ✓ Machine Vision 3D Camera
- ✓ Automated Optical Inspection



Applications

Surface Metrology

3D Shape

Roughnes

Corrosion analysis

Z Depth

Digs , scratches QC

Surface inspection

Industries

Metal Tooling

Printed Board

Medica

Automotive

Aerospace

Semiconductor

Solar Cell

Electric

Food

Packaging

Wood

Flooring

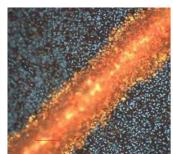
Adhesive Reads

Weld Seams

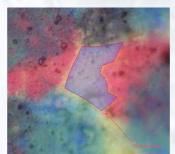
- Smart 3D vision •
- No Moving Parts
- All-In-One Device
- Maintenance Free •
- Affordable Solution
- Easy Implementation

High Resolution Digital Microscope Camera

Megapixel CCD • 2D Measurements • Graphics Overlay • Report





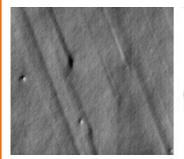


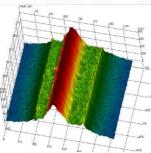


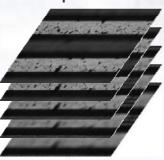
ZeeScope provides sharp & crisp digital images in real time, featuring all necessary tools for digital image documentation in high resolution.

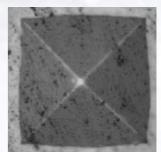
Multiple Imaging Capabilities

AutoFocus • Depth Measurement • Z-Stacking • Extended Depth of Field • 3D Reconstruction





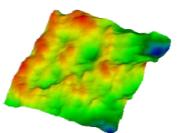


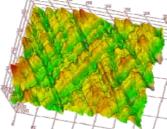


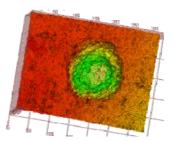
Thanks to its integrated ZeeScan module, the 3D Digital Microscope performs all critical tasks in material microscopy while using a standard upright or inverted microscope.

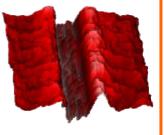
3D Surface Metrology

Surface Shape • Roughness • Waviness • Step Height









ZeeScope is the quickest and easiest way for precise surface topography measurements compared to complex, bulky and expensive systems.





Software

- GetPhase® GUI software (included) is compatible with Windows 8, 7, XP & Vista. GetPhase® provides comprehensive tools from automatic acquisition to 2D / 3D image analysis, documentation and reports. Including Z-stacking, Z height measurement, Image fusion (Extended Depth of Field), 3D reconstruction and measurements, multiple display modes: DIC, Phase, brightfield, darkfield, surface and profile roughness, step height measurements.
- API / SDK (optional) for controlling ZeeScope acquisition, routines for Z-stack, 3D reconstruction, EDF, DIC, Phase, and 3D surface analysis.

 Acquisition 	& Processing
---------------------------------	--------------

2D/3D Display & Analysis

Image Data Export & Report

- 2D / 3D Acquisition Wizard - BF, DF, Ph, DIC, 3D views

- Auto Focus & Exposure

- Text & Graphics overlay

- 2D / 3D measurements

- Region-of-Interest

- Macro Recording

- Image fusion (EDF)

- Navigator

- Roughness ISO standards

- Stitching

- Step Height Measurements

- Project Archiving

- 3D Data in Excel Format

- 3D Data for 3rd Party Software

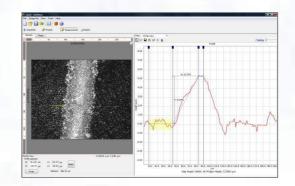
- Report Editor

- HTML Compatible Presentation

Powerful Imaging Tool

Z-stacking of high resolution images can be automatically achieved providing image fusion image (Extended depth of Fiel image, Z depth measurement or 3D reconstruction. In addition, GetPhase provides 2D measurements and image documentation tools.

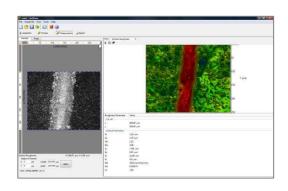
- Reveals finest structure details without specialized optics
- On click Image documentation with multiple views
- Automatic image fusion (Extended Depth of Field)
- 2D measurements & report



Fast & Accurate 3D Surface Metrology

ZeeScan with GetPhase performs 3D acquisition and analysis in a remarkable fast and easy way. Non contact optical surface profiling is highly repeatable.

- 3D surface analysis in micrometer and nanometer range
- Measurement capabilities from smooth to rough surfaces
- ISO Roughness and step heights measurements
- High throughput thanks to fast acquisition & processing time





Smart Hardware Architecture

ZeeScope is an all-in one 3D digital microscope controlled by PC with a single USB2 connection and integrating the proprietary PhaseView ZeeScan optical assembly. Accurate calibration is achieved using an automated procedure and stored in an internal memory to prevent any losses.

	ZeeScope 100	ZeeScope 150	ZeeScope 200
Camera	½"CMOS 1280 x 1024 5.2µm square pixels 30fps@full resolution	1/1.8"CCD 1616 x 1216 4.40 square pixels 12fps@full resolution	½"CCD 2560 x 1920 2.20 square pixels 6fps@full resolution
Light source	Built-in coaxial LED light source		
Objectives	Interchangeable objectives (Finite - Infinite type) adapter provided for threads RMS and M25/0.75		
Dimensions & weight ZeeScope Head Control unit	225(H) x 40 (W) x 55(D) mm, 425g 40(H) 158(W) 150(D) mm, 150g		
Power supply	110/220V AC		
PC interface		USB 2.0	

3D Measurement Performance

Z range and resolution are objective and c-mount coupler magnification dependant. The table here under gives typical performance for standard objective magnification. For any other magnification, the following formulas can be applied:

 $Z Range = 60mm / (G_Obj)^2$

Z Resolution = Objective Depth Of Field /4

G_Obg = Objective magnification

Objective Mag / NA	Z Range (μm)	Z Resolution (μm)
5X / 0.10	2400	18.5
10X / 0.25	600	3
20X / 0.45	150	1
50X / 0.8	24	0.25

Z accuracy:	1%	
Z Repeatability:	0.35%	
Max slope: 90°		
XY Spatial resolution determined by camera		
resolution and objective magnification		

Roughness Measurement

12 analysis parameters are provided in total, including the frequently-used Ra (Sa), Rq (Sq), Rz (Sz), parameters. Parameters conform to ISO 4287, 25178 DIN 4768

Measuring range: Ra, Rq: 0.01-500μm Measuring accuracy: ≤±10% Repeatability: ≤6%

